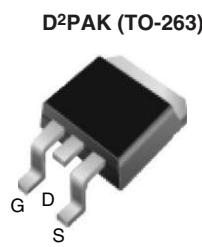


Power MOSFET

PRODUCT SUMMARY	
V _{DS} (V)	- 100
R _{DS(on)} (Ω)	V _{GS} = - 10 V 0.20
Q _g (Max.) (nC)	61
Q _{gs} (nC)	14
Q _{gd} (nC)	29
Configuration	Single



FEATURES

- Surface Mount
- Available in Tape and Reel
- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- P-Channel
- 175 °C Operating Temperature
- Fast Switching
- Lead (Pb)-free Available



RoHS*
COMPLIANT

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The D²PAK (TO-263) is a surface mount power package capable of accommodating die sizes up to HEX-4. It provides the highest power capability and the lowest possible on-resistance in any existing surface mount package. The D²PAK (TO-263) is suitable for high current applications because of its low internal connection resistance and can dissipate up to 2.0 W in a typical surface mount application.

ORDERING INFORMATION

Package	D ² PAK (TO-263)	D ² PAK (TO-263)
Lead (Pb)-free	IRF9540SPbF SiHF9540S-E3	IRF9540STRLPbFa SiHF9540STL-E3 ^a
SnPb	IRF9540S SiHF9540S	IRF9540STRL ^a SiHF9540STL ^a

Note

a. See device orientation.

ABSOLUTE MAXIMUM RATINGS T_C = 25 °C, unless otherwise noted

PARAMETER	SYMBOL	LIMIT	UNIT
Drain-Source Voltage	V _{DS}	- 100	V
Gate-Source Voltage	V _{GS}	± 20	
Continuous Drain Current	I _D	- 19	A
		- 13	
Pulsed Drain Current ^a	I _{DM}	- 72	
Linear Derating Factor		1.0	W/°C
Linear Derating Factor (PCB Mount) ^e		0.025	
Single Pulse Avalanche Energy ^b	E _{AS}	640	mJ
Repetitive Avalanche Current ^a	I _{AR}	- 19	A
Repetitive Avalanche Energya	E _{AR}	15	mJ
Maximum Power Dissipation	P _D	150	W
		3.7	
Peak Diode Recovery dV/dt ^c	dV/dt	- 5.5	V/ns
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to + 175	°C
Soldering Recommendations (Peak Temperature)	for 10 s	300 ^d	

Notes

- Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- V_{DD} = - 25 V, starting T_J = 25 °C, L = 2.7 mH, R_G = 25 Ω, I_{AS} = - 19 A (see fig. 12).
- I_{SD} ≤ - 19 A, dI/dt ≤ 200 A/μs, V_{DD} ≤ V_{DS}, T_J ≤ 175 °C.
- 1.6 mm from case.
- When mounted on 1" square PCB (FR-4 or G-10 material)

* Pb containing terminations are not RoHS compliant, exemptions may apply

THERMAL RESISTANCE RATINGS

PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient (PCB Mount) ^a	R _{thJA}	-	-	40	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	-	1.0	

Note

- a. When mounted on 1" square PCB (FR-4 or G-10 material).

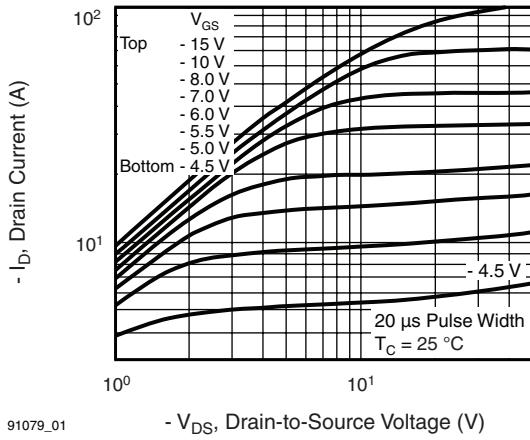
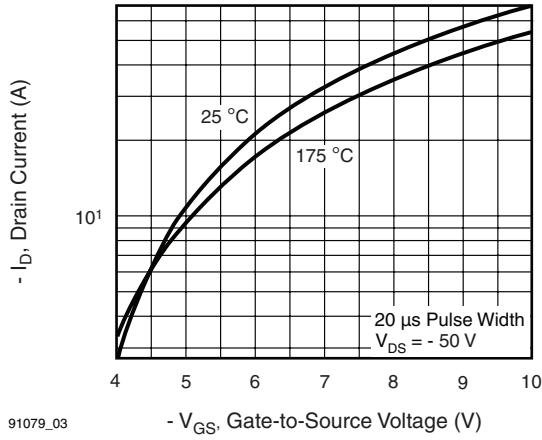
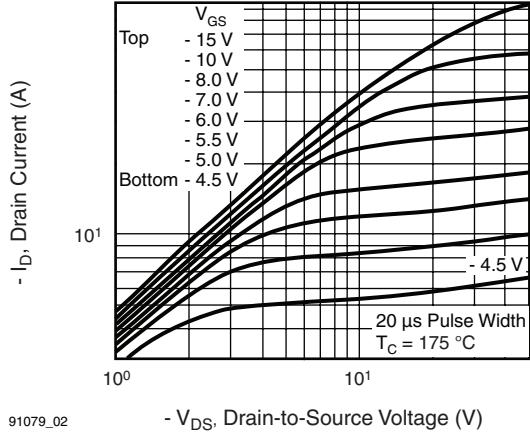
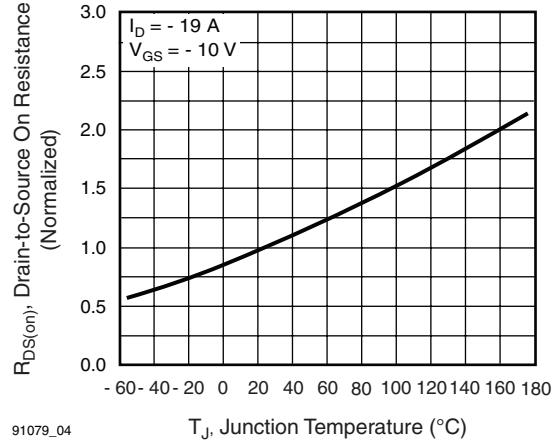
SPECIFICATIONS T_J = 25 °C, unless otherwise noted

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = - 250 μA		- 100	-	-	V
V _{DS} Temperature Coefficient	ΔV _{DS} /T _J	Reference to 25 °C, I _D = - 1 mA		-	- 0.087	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = - 250 μA		- 2.0	-	- 4.0	V
Gate-Source Leakage	I _{GSS}	V _{GS} = ± 20 V		-	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = - 100 V, V _{GS} = 0 V		-	-	- 100	μA
		V _{DS} = - 80 V, V _{GS} = 0 V, T _J = 150 °C		-	-	- 500	
Drain-Source On-State Resistance	R _{D(on)}	V _{GS} = - 10 V I _D = - 11 A ^b		-	-	0.20	Ω
Forward Transconductance	g _f	V _{DS} = - 50 V, I _D = - 11 A		6.2	-	-	S
Dynamic							
Input Capacitance	C _{iss}	V _{GS} = 0 V, V _{DS} = - 25 V, f = 1.0 MHz, see fig. 5		-	1400	-	pF
Output Capacitance	C _{oss}			-	590	-	
Reverse Transfer Capacitance	C _{rss}			-	140	-	
Total Gate Charge	Q _g	V _{GS} = - 10 V I _D = - 19 A, V _{DS} = - 80 V, see fig. 6 and 13 ^b		-	-	61	nC
Gate-Source Charge	Q _{gs}			-	-	14	
Gate-Drain Charge	Q _{gd}			-	-	29	
Turn-On Delay Time	t _{d(on)}			-	16	-	
Rise Time	t _r	V _{DD} = - 50 V, I _D = - 19 A, R _G = 9.1 Ω, R _D = 2.4 Ω, see fig. 10 ^b		-	73	-	ns
Turn-Off Delay Time	t _{d(off)}			-	34	-	
Fall Time	t _f			-	57	-	
Internal Drain Inductance	L _D		Between lead, 6 mm (0.25") from package and center of die contact	-	4.5	-	nH
Internal Source Inductance	L _S			-	7.5	-	
Drain-Source Body Diode Characteristics							
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	- 19	A
Pulsed Diode Forward Current ^a	I _{SM}	-		-	- 72		
Body Diode Voltage	V _{SD}	T _J = 25 °C, I _S = - 19 A, V _{GS} = 0 V ^b		-	-	- 5.0	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = - 19 A, dI/dt = 100 A/μs ^b		-	130	260	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	0.35	0.70	nC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L _S and L _D)					

Notes

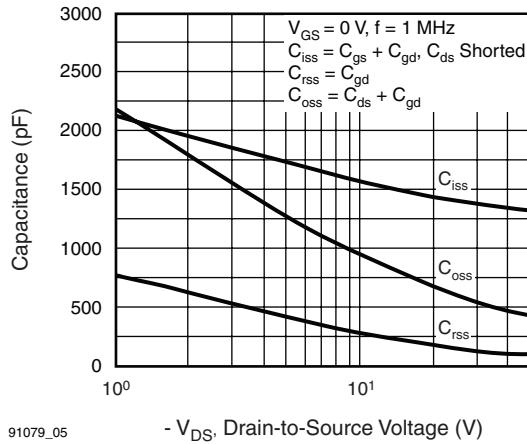
- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

- b. Pulse width ≤ 300 μs; duty cycle ≤ 2 %.

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Fig. 1 - Typical Output Characteristics, $T_C = 25 \text{ } ^\circ\text{C}$

Fig. 3 - Typical Transfer Characteristics

Fig. 2 - Typical Output Characteristics, $T_C = 175 \text{ } ^\circ\text{C}$

Fig. 4 - Normalized On-Resistance vs. Temperature

IRF9540S, SiHF9540S

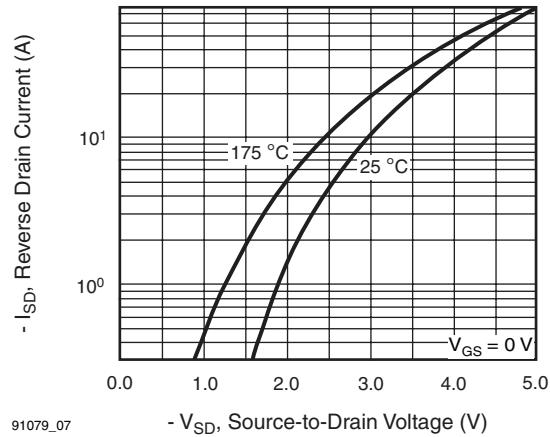
Vishay Siliconix



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$-V_{DS}$, Drain-to-Source Voltage (V)

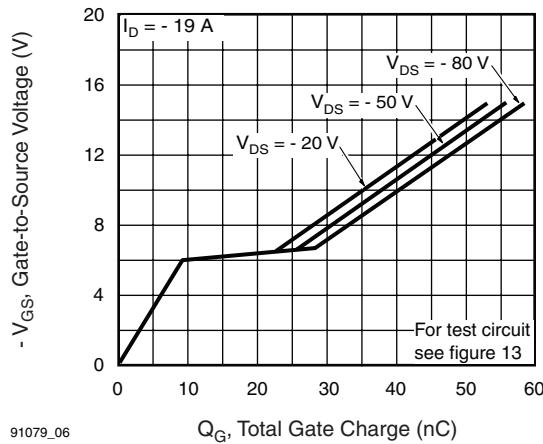
Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage



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$-V_{SD}$, Source-to-Drain Voltage (V)

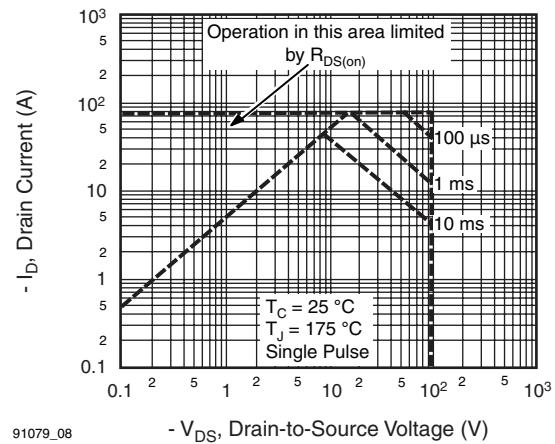
Fig. 7 - Typical Source-Drain Diode Forward Voltage



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Q_G , Total Gate Charge (nC)

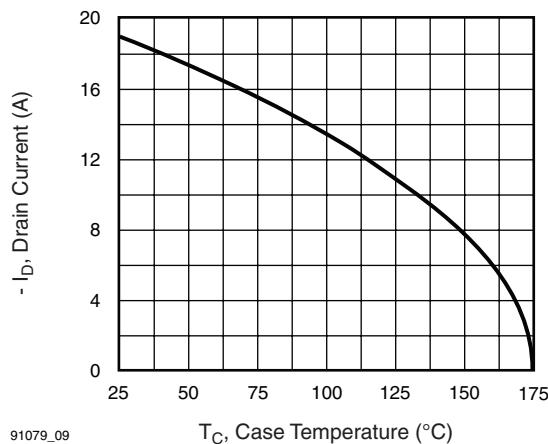
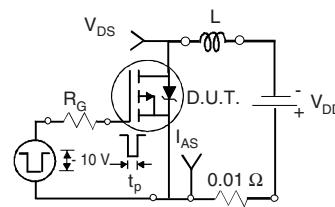
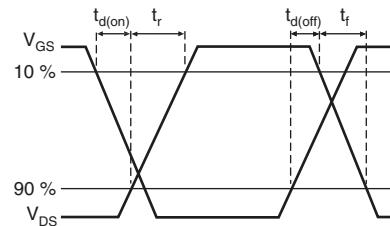
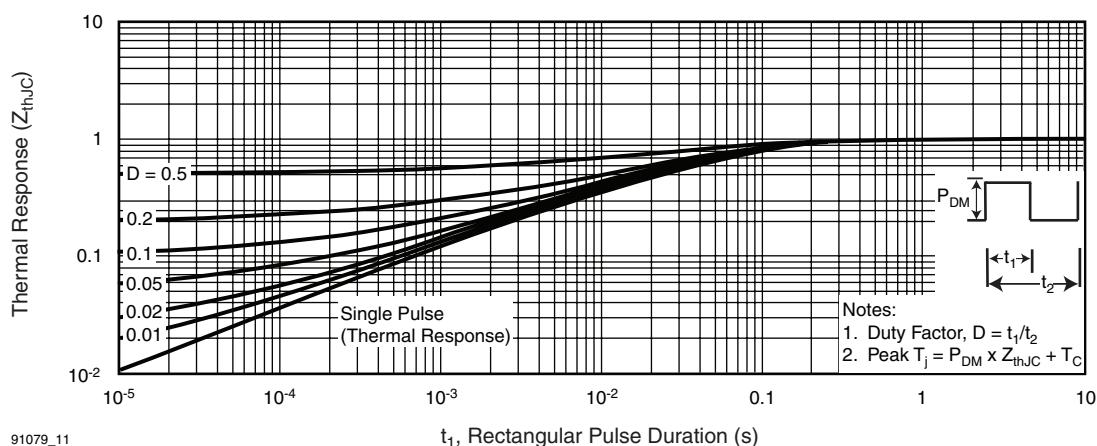
Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



91079_08

$-V_{DS}$, Drain-to-Source Voltage (V)

Fig. 8 - Maximum Safe Operating Area


Fig. 9 - Maximum Drain Current vs. Case Temperature

Fig. 10a - Switching Time Test Circuit

Fig. 10b - Switching Time Waveforms

Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

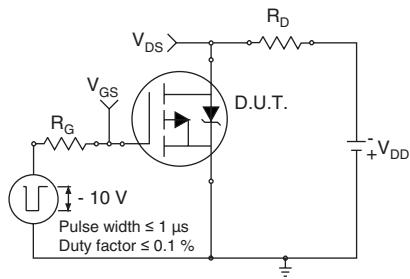


Fig. 12a - Unclamped Inductive Test Circuit

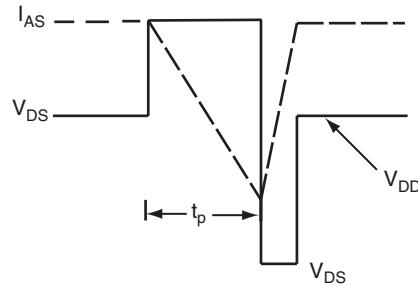


Fig. 12b - Unclamped Inductive Waveforms

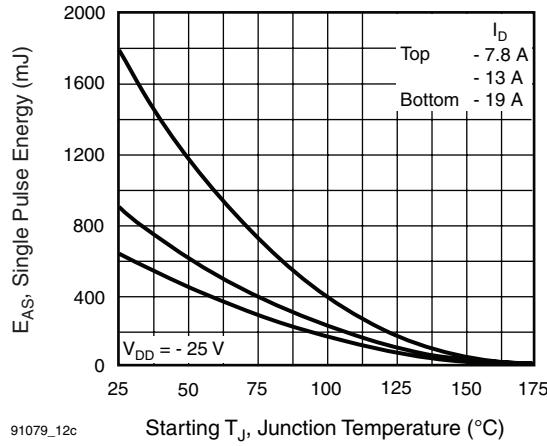


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

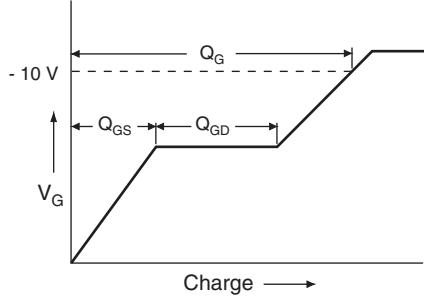


Fig. 13a - Basic Gate Charge Waveform

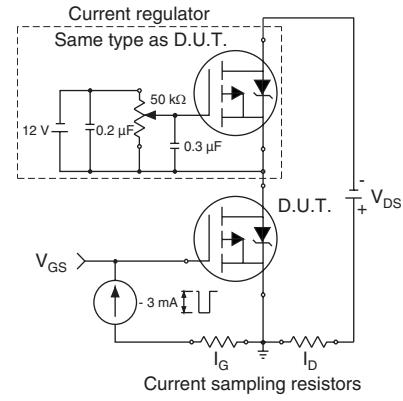


Fig. 13b - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit

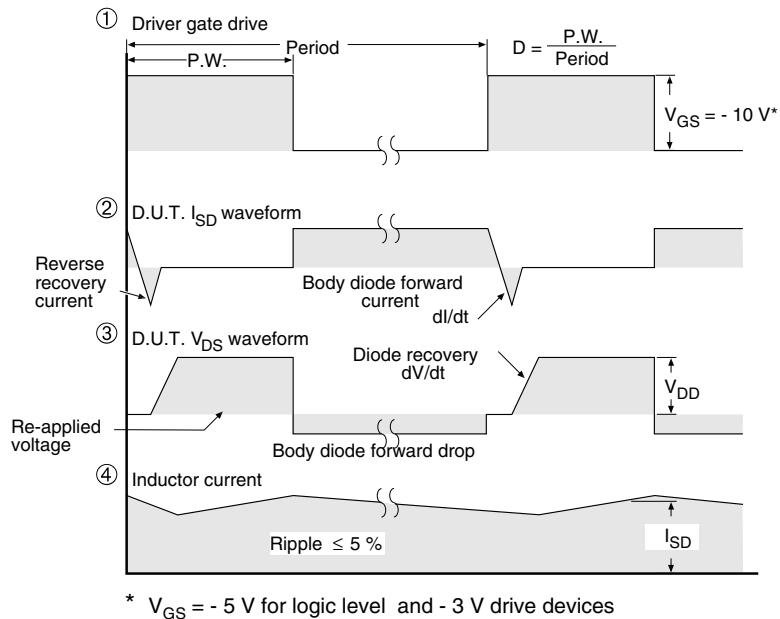
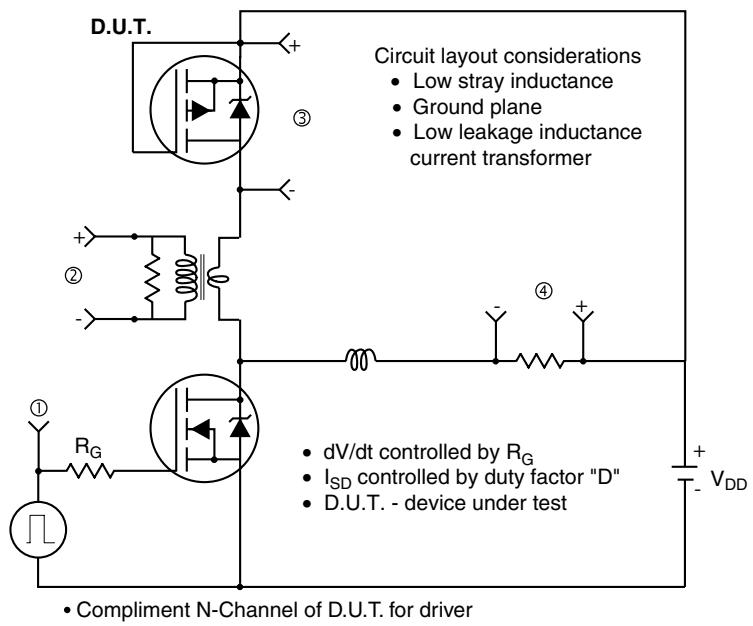


Fig. 14 - For P-Channel

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